

AUTOMOTIVE HYBRID CURRENT TRANSDUCER SHUNT AND OPEN LOOP HALL TECHNOLOGY HSU01





Introduction

The HSU is a hybrid current transducer for DC & AC measurement of the battery packs in electric and hybrid vehicles

HSU has 2 different current measurement channels: Shunt and hall effect.

Features

- · High insulation level
- Unipolar +5 V DC power supply for HALL
- Primary current measuring range up to ±2000 A (1 s) both Shunt and Hall
- Maximum RMS primary admissible current: defined by the busbar, the magnetic core or ASIC T < +125 °C
- Operating temperature range: -40 °C < T < +125 °C
- Output voltage: fully ratio-metric (in sensitivity and offset) for Hall effect channel.

Advantages

- Excellent accuracy
- Very good linearity
- · Very low thermal offset drift
- · Very low thermal sensitivity drift.

Automotive applications

- · Battery management
- EV, Hybrid and utility vehicles
- The HSU Family is designed to run in a vehicle battery pack or in a Battery Disconnect Unit and cannot be used in an environment exposed to water projections or gravel projections. The HSU is compliant with Functional Safety standard ISO 26262. The test items used to validate the product are described at the end of the document
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Principle of HSU - Shunt channel

There'll be a voltage drop when current goes through shunt, and current can be deduced by Ohm's Law, I = U / R_Shunt.

Principle of HSU - Hall effect channel

The open loop transducers use a Hall effect integrated circuit. The magnetic flux density B, contributing to the rise of the Hall voltage, is generated by the primary current $I_{\rm p}$ to be measured.

The current to be measured I_p is supplied by a current source i.e. battery or generator (Figure 1).

Within the linear region of the hysteresis cycle, ${\it B}$ is proportional to:

$$B(I_p) = a \times I_p$$

 $I_{\rm Hall}$

The Hall voltage is thus expressed by:

$$U_{\text{Hall}} = (c_{\text{Hall}} / d) \times I_{\text{Hall}} \times a \times I_{\text{P}}$$

Except for $I_{\rm p}$, all terms of this equation are constant. Therefore:

$$U_{\rm Hall} = b \times I_{\rm P}$$
 a constant b constant $c_{\rm Hall}$ Hall coefficient d thickness of the Hall plate

The measurement signal $U_{\mbox{\tiny Hall}}$ is amplified to calculate the user output voltage or current.

current across the Hall plate

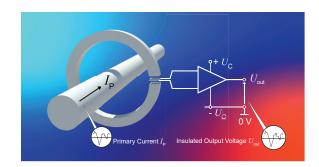
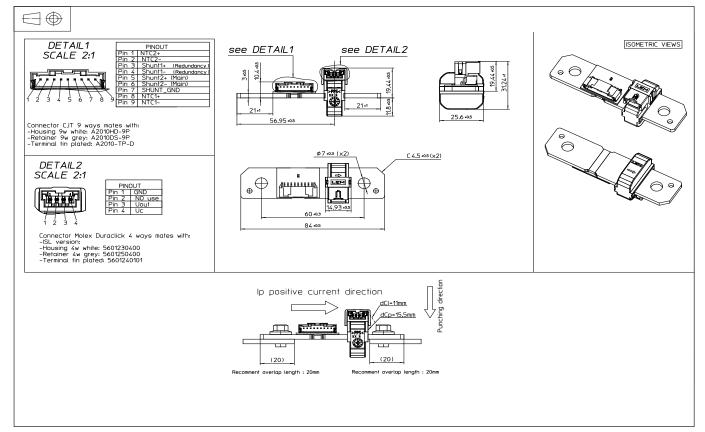


Fig. 1: Principle of the open loop transducer



Dimensions (in mm) HSU01



Mechanical characteristics

• Refer to Outline Drawing.

Mounting recommendation

Assembly torque

M6 Screw with 8-10 N·m.

Note: The installation planar should have a flatness tolerance of ≤0.2 mm. The size tolerances of the installation bracket and nut, as well as the use of installation tools and fixtures, have an impact on the maximum installation torque of the product. If there are any relevant design or process changes from customer side, it is advisable to implement them after verification.

Remark

 U_{out} > U_O when I_P flows in the positive direction (see arrow on drawing).

NTC Simplified formula

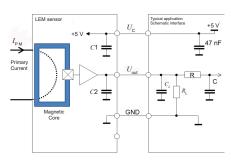
$$T = 1/\left(\frac{R_{\text{NTC}}}{10000}\right)/B + \frac{1}{273.15 + 25}\right) - 273.15$$

Notes: 1) NTC type: NCU18XH103F6SRB

²⁾ Main NTC is measured in Pin8 and Pin9
Redundancy NTC is measured in Pin1 and Pin2.

Redundancy NTC is measured in Pin1 and Pin2, currently reserved.

System architecture (Hall)

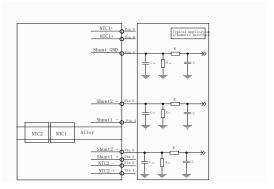


 $C_{\rm L}$ < 100 nF EMC protection (optional)

 $R_1 \ge 10 \text{k Ohm}$

RC Low pass filter (optional)

System architecture (Shunt)



 $C_{\rm Ls}$ & $R_{\rm Ls}$ Value is based on system design(optional) RC Low pass filter(Optional)

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Absolute ratings (not operating)

Downwater	Cumbal	Complete Harit	Specification			Conditions
Parameter	Symbol	Unit	Min	Typical	Max	Conditions
Maximum supply voltage	$U_{\rm C\; max}$	V	-14		14	Continuous, not operating
Ambient storage temperature	T_{Ast}	°C	-40		125	
Electrostatic discharge voltage (HBM - Human Body Model)	$U_{\rm ESD\; HBM}$	kV			8	
RMS voltage for AC insulation test	U_{d}	kV			4.2	50 HZ,1 min, IEC 60664 part1
Creepage distance	d_{Cp}	mm		15.5		
Clearance	d_{CI}	mm		11		
Comparative tracking index	CTI	-		PLC3		
Maximum output current	$I_{ m out\; max}$	mA	-10		10	
Maximum output voltage	$U_{ m out\; max}$	V	-14		14	
Insulation resistance	R_{INS}	ΜΩ	500			

Operating characteristics in nominal range ($I_{\rm P\,N}$) For SHUNT

Davamatav	Cumbal	Unit	Specification			Conditions	
Parameter	Symbol	Ullit	Min	Typical	Max	Conditions	
Resistance value	R	μΩ	47.5		52.5	@ 25 °C	
Temperature coefficient of resistance	a_{R}	PPM/°C	-200		200	@ 25 ~ 125 °C	
Operating temperature	T	°C	-40		125	Based on NTC temperature	

Note: ¹⁾ Definition of resistance tolerance is measured between Pin5 and Pin6 Resistance value between Pin3 and Pin4 is for reference only.

Operating characteristics in nominal range ($I_{\rm P\,N}\!)$ FOR HALL

Danamatan	Country of	Hadis	S	pecification	n	Conditions
Parameter	Symbol	Unit	Min	Typical	Max	Conditions
		Electrica	l Data	1		
Supply voltage	U_{c}	V	4.75	5	5.25	
Ambient operating temperature	T_{A}	°C	-40		125	
Output voltage (Analog) 1)	U_{out}	V	$U_{\text{out}} = (U$	$(_{\rm c}/5) \times (U_{\rm o})$	$+ S \times I_P$)	
Offset voltage	U_{o}	V		2.5		@ U _c = 5 V
Current consumption	I_{C}	mA		15		@ $U_{\rm C}$ = 5 V, @ $T_{\rm A}$ = 25 °C, @ $I_{\rm P}$ = 0 A
Load resistance	R_{L}	ΚΩ	10			
Output internal resistance	$R_{ m out}$	Ω		1	10	
		Performan	ce Data			
Ratiometricity error	$\varepsilon_{ m r}$	%		±0.3		@ T _A = 25 °C
Sensitivity error	$\varepsilon_{_{ m S}}$	%		±1		@ $T_{\rm A}$ = 25 °C, @ $U_{\rm C}$ = 5 V
Electrical offset voltage	U_{OE}	mV		±3		@ $T_{\rm A}$ = 25 °C, @ $U_{\rm C}$ = 5 V
Magnetic offset voltage	U_{OM}	mV		±1		@ $T_{\rm A}$ = 25 °C, @ $U_{\rm C}$ = 5 V
Average temperature coefficient of $U_{\mathrm{O}\mathrm{E}}$	$TCU_{ extsf{OEAV}}$	mV/°C		±0.04		@ -40 °C < T _A < 125 °C
Average temperature coefficient of S	TCS_{AV}	%/°C	-0.03	±0.01	0.03	@ -40 °C < T _A < 125 °C
Linearity error	ε_{L}			±1		@ $U_{\rm C}$ = 5 V, @ $T_{\rm A}$ = 25 °C
Frequency bandwidth 2)	BW	Hz		35		@ -3 dB
Peak-to-peak noise voltage	$U_{\rm nopp}$	mV		10		@ DC to 1 MHz
Output RMS noise voltage	U_{no}	mV		1.5		@ DC to 1 MHz
Start-up time	$t_{ m start}$	ms			1	
Settling time after overload	$t_{\rm s}$	ms			10	

 $\underline{\text{Notes}}\text{:} \qquad ^{1)} \quad \text{The output voltage } U_{\text{out}} \text{ is fully ratiometric. The offset and sensitivity are dependent on the supply voltage } U_{\text{C}} \text{ relative to the following formula:}$

$$I_{P} = \left(\frac{5}{U_{C}} \times U_{\text{out}} - U_{O}\right) \times \frac{1}{S} \text{ with } S \text{ in (V/A)}$$

Primary current frequencies must be limited in order to avoid excessive heating of the busbar, magnetic core and the ASIC (see feature paragraph in page 1).





SHUNT

Davamatav	Symbol	mbol Unit	Specification			Conditions
Parameter			Min	Typical	Max	Conditions
		Electric	al Data			
Primary current, measuring range	I_{PM}	Α	-2000		2000	Duration ≤ 1 s
Primary nominal RMS current	I_{PN}	А	-400		400	

HALL

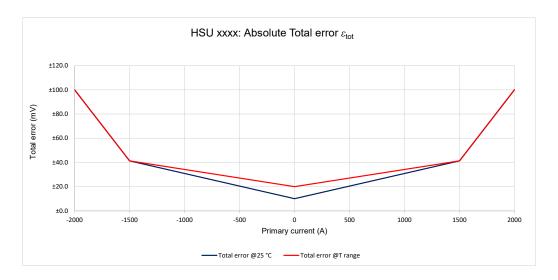
Davamatav	Cymhal Iluit		S	pecificatio	n	Conditions
Parameter	Symbol	Unit	Min	Typical	Max	Conditions
Electrical Data						
Primary current, measuring range	I_{PM}	Α	-2000		2000	
Sensitivity	S	mV/A		1		@ U _c = 5 V

Care note for storage

The shunt current module shall be stored in an environment where temperature and humidity must be controlled (temperature 5 °C to 35 °C, humidity < 60 % RH) . However, the humidity should be maintained as low as possible.



Total error $\varepsilon_{\mathrm{tot}}$ HALL



Primary current	То	tal error @ 25	°C	Tota	al error @ <i>T</i> ra	nge
(A)	(mV)	Α	(%) $I_{\rm PM}^{-1)}$	(mV)	(A)	(%) $I_{\rm PM}^{-1)}$
-2000	100	100	5.00 %	100	100	5.00 %
-1500	41.25	41.25	2.06 %	41.25	41.25	2.06 %
0	10	10	-	20	20	-
1500	41.25	41.25	2.06 %	41.25	41.25	2.06 %
2000	100	100	5.00 %	100	100	5.00 %

 $\underline{\text{Note}}\textsc{:}$ $\ ^{\text{1)}}$ Hall channel accuracy calculated by I_{PM} .



Derating curve

Setup

Cor		

- Inside climate chamber
- 25 °C setting up in chamber
- Test cable: copper(150mm²)
 Mounting: refers to picture
- Test points: alloy

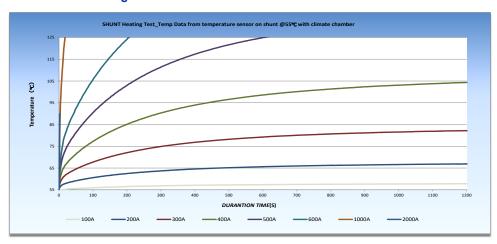
HSU:

- Cu-OF

- Section: 3 x 20 (mm)

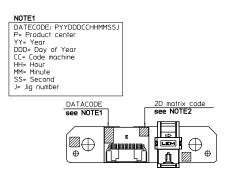
- Length: 84 mm

Heating generation chart according to above condition



Notes: Depending on the conditions of use, the temperature of the exposed parts of Shunt alloy may reach or exceed 125°C.

DATACODE & 2D Matrix Code

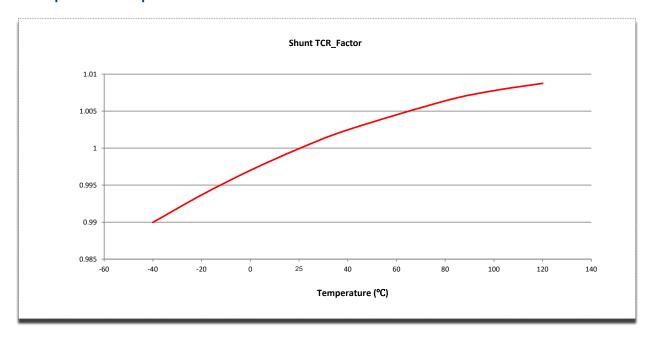


Module Info.	PCBA Part No(11 digits)	xxxxxxxxxx
	Version(3 digits)	XXX
	Production date(6 digits)	YYMMDD
	Production Number(5 digits)	XXXXX
Shunt Info.	Year(4 digits)	YYYY
	Month(2 digits)	MM
	Day(2 digits)	DD
	Module ID(5 digits)	XXXXX
	Resistance R25(7 digits)	Rxxxxxn
	A:Quadratic coefficient(12 digits)	±X.XXXXXXXXX
	B:First-order coefficient(12 digits)	±X.XXXXXXXXX
	C:Constant(12 digits)	±X.XXXXXXXX

 \star R25 is shunt resistance at 25°C, unit: n0hm



Shunt Temperature Compensation infomation



Generic compensation factor for resistance of shunt need to be multiplied with:

 $R_{\text{temp}} = R_{25}^* (A^* T^2 + B^* T + C).$

Where:

 R_{temp} is the compensated from the factor for shunt resistance drift over temperature normalized to 1 at 25 °C. T is temperature reading from PCB temperature transducer NTC.

A is quadratic coefficient, the default value is -0.xxxxxxxxx.

B is first-order coefficient, the default value is +0.xxxxxxxxx.

C constant term coefficient, the default value is +0.xxxxxxxxx.

R₂₅ is resistance value of shunt at 25 °C.

Functional Safety

Functional Safety Functional Safety Top Level Safety Requirement HSU (Hall effect channel) – SR1 Current sensor error

Item1	Definitions
LEM Description	The sensor shall provide a valid current measurement value when the error versus the target value is lower than 10 %. The sensor accuracy error is below 5 % in the current ranges: [-2000 A; -1500 A [and] +1500 A; +2000 A]; in the current range [-1500 A; +1500 A] with an error
	below 2.75 %, and with offset less than 20 mV when I_p = 0.
ASIL	A(D)
Operation Conditions	Running (when sensor is supplied)
FHTI	Less than 20ms (1)
Safe state	No sensor internal safe state for accuracy error only for internal integrity failure (2)

(1) Detailed Note for FHTI:
5ms in case of Power supply failure
Immediate in case of Memory failure
20ms in case of Broken Supply Wire or ADC Output Clipping

(2) Note for Safe state

Power supply failure: Sensor Output value set to GND (external pull-down resistor required)

Memory Failure: Sensor output value goes to (0~0.2)%* $U_{\rm C}$ or (96~100)%* $U_{\rm C}$. [$U_{\rm C}$ shall be within [4.75V, 5.25V].]

Broken Supply Wire: Sensor output goes to V = (500nA Max) * RL. [RL shall

be no less than 10Kohm.][All temperature range with $U_{\rm C}$ = 5V]

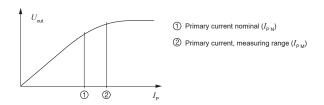
ADC Output Clipping: Sensor output value goes to (0~0.2)% $^*U_{\rm C}$ or

(96~100)%* U_{C} . Page 7/10



PERFORMANCES PARAMETERS DEFINITIONS

Primary current definition:



Definition of typical, minimum and maximum values:

Minimum and maximum values for specified limiting and safety conditions have to be understood as such as values shown in "typical" graphs. On the other hand, measured values are part of a statistical distribution that can be specified by an interval with upper and lower limits and a probability for measured values to lie within this interval. Unless otherwise stated (e.g. "100 % tested"), the LEM definition for such intervals designated with "min" and "max" is that the probability for values of samples to lie in this interval is 99.73 %. For a normal (Gaussian) distribution, this corresponds to an interval between -3 sigma and +3 sigma. If "typical" values are not obviously mean or average values, those values are defined to delimit intervals with a probability of 68.27 %, corresponding to an interval between -sigma and +sigma for a normal distribution. Typical, minimum and maximum values are determined during the initial characterization of a product.

Output noise voltage:

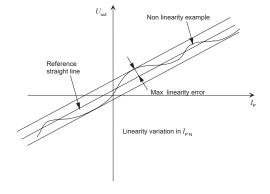
The output voltage noise is the result of the noise floor of the Hall elements and the linear amplifier.

Magnetic offset:

The magnetic offset is the consequence of an any current on the primary side. It's defined after a stated excursion of primary current.

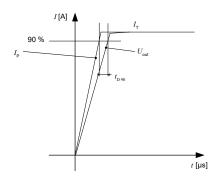
Linearity:

The maximum positive or negative discrepancy with a reference straight line $U_{\rm out}$ = $f(I_{\rm P})$. Unit: linearity (%) expressed with full scale of $I_{\rm P\,N}$.



Delay time $t_{D 90}$:

The time between the primary current signal (I_{PN}) and the output signal reach at 90 % of its final value.



Sensitivity:

The transducer's sensitivity S is the slope of the straight line $U_{\text{out}} = f(I_{\text{P}})$, it must establish the relation:

$$U_{\text{out}}(I_{\text{P}}) = U_{\text{C}}/5 (S \times I_{\text{P}} + U_{\text{O}})$$

Offset with temperature:

The error of the offset in the operating temperature is the variation of the offset in the temperature considered with the initial offset at 25 °C.

The offset variation $I_{\text{O}\,\textsc{T}}$ is a maximum variation the offset in the temperature range:

$$I_{OT} = I_{OE} \max - I_{OE} \min$$

The offset drift $TCI_{\text{O E AV}}$ is the $I_{\text{O }T}$ value divided by the temperature range.

Sensitivity with temperature:

The error of the sensitivity in the operating temperature is the relative variation of sensitivity with the temperature considered with the initial offset at 25 °C.

The sensitivity variation S_{τ} is the maximum variation (in ppm or %) of the sensitivity in the temperature range: S_{τ} = (Sensitivity max - Sensitivity min) / Sensitivity at 25 °C. The sensitivity drift TCS $_{\mathrm{AV}}$ is the S_{T} value divided by the temperature range. Deeper and detailed info available is in our LEM technical sales offices (www.lem.com).

Offset voltage @ $I_p = 0$ A:

The offset voltage is the output voltage when the primary current is zero. The ideal value of $U_{\rm O}$ is $U_{\rm C}{\rm J}$ 2. So, the difference of U_0 – U_c / 2 is called the total offset voltage error. This offset error can be attributed to the electrical offset (due to the resolution of the ASIC quiescent voltage trimming), the magnetic offset, the thermal drift and the thermal hysteresis. Deeper and detailed info available is in our LEM technical sales offices (www.lem. com).





Verification Plan

Tests	Standard	Specific Conditions		
	ELECTRICAL PERFORMANC	ES		
Frequency bandwidth		$U_{\rm C}$ = 5 V, 30 Hz to 100 kHz; At 20 A peak		
	ENVIRONMENTAL TESTS (Clim	natic)		
Ageing 85 °C /93 % <i>RH</i>	IEC 60068-2-78 (2012)	T = 85 °C; RH = 85 %; Duration = 1000 h $U_{\rm C}$ = 5 V; $I_{\rm p}$ = 0 A; Monitoring each 60 min		
Low temperature storage	ISO 16750-4 § 5.1.1.1 (04/2010)	T = -40 °C Duration = 500 h		
High temperature storage	ISO 16750-4 § 5.1.2.1 (04/2010)	T = 125 °C Duration = 1000 h		
Power temperature cycle test	ISO 16750-4 § 5.3.1 (04/2010)	30 cycles (240 h), -40 °C /125 °C Shunt: $I_{\rm p}$ = 600 A ((30min each test,contuine 10S)) Hall: $U_{\rm C}$ = 5 V , monitoring $U_{\rm out}$ @ 0 A ((30min each test))		
Thermal shock	ISO 16750-4 § 5.3.2 (2023)	T = -40 °C & 125 °C Duration = 300 cycles 30 min/30 min $U_{\rm C}$ = NO power supply (unconnected) and No wiring harness		
	ENVIRONMENTAL TESTS (Mech	anical)		
Random Vibration	ISO 16750-3 § 4.1.x (12/2012)	Temperature -40 °C /125 °C RMS acceleration 27.1 m/s², 10 to 1000 Hz		
Mechanical Shocks	ISO 16750-3 § 4.2 (12/2012)	Pulse shape: half sine, 50 G, 6 ms 10 shocks per direction (total 60)		
	SAFETY - Insulation tests			
Insulation test	ISO 16750-2 § 4.11 (11/2012)	$T_{\rm A}$ = 25 °C $U_{\rm d}$ = 4.26 kV RMS (50 Hz) for 60 s		
Insulation resistance	ISO 16750-2 § 4.12 (12/2012)	DC = 1000 V RMS (50 Hz) for 60 s Criteria: ≥ 500 M Ohm		
	EMC TESTS			
Immunity to Electrostatic Discharges (Handling of devices)	ISO 10605 (07/2008)	Contact discharges: ± 4 kV; Air discharges: ± 8 kV $U_{\rm C}$ = 0		
Immunity to Radiated disturbances (ALSE)	ISO 11452-2 (2019)	f = 400 MHz to 1 GHz; Level = 100 V/m (CW, AM 80 %) f = 0.8 GHz to 2 GHz; Level = 70 V/m (CW, PM PRR = 217 Hz PD = 0.57 ms) f = 1 GHz to 2 GHz; Level = 70 V/m (CW)		
Immunity to Conducted disturbances (BCI)	ISO 11452-4 (12/2020)	f = 1 MHz to 400 MHz		
Emission Radiated (ALSE)	CISPR 25 § 6.5 (2021)	f= 150 kHz to 6 GHz		





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